

TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

T7988, JT7988Y-AS

T7988, JT7988Y-AS CMOS 1 CHIP LSI FOR LCD ELECTRONIC CALCULATOR

The T7988, JT7988Y-AS is a 1 chip microcomputer for 10-digits + 2-digits electronic scientific calculator.

T7988, JT7988Y-AS is the complete single chip CMOS LSI for electronic calculator with 10 digit, 67 function, 3 expression and hexadecimal, octal and binary, statistic calculation, fractional number calculation, and logic operation with the following features.

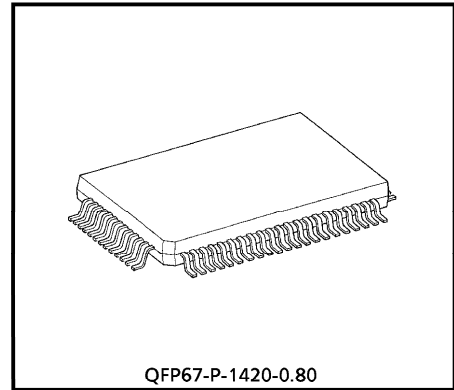
FEATURES

- Display 12 display digits plus 2 digits code at the right margin.
 - Scientific and engineering display.
Mantissa 10 digits plus exponent 2 digits plus negative code 2 digits.
 - Other than above
Mantissa 10 digits plus negative code 1 digit.

- 13 kinds of special display

M	Memory	HEX	Hexadecimal mode
-	Mantissa and exponent Minus	SD	Statistic calculation mode
E	Error	DEG	Degree
INV	Inverse	RAD	Radian
HYP	Hyperbolic	GRAD	Gradian
BIN	Binary mode	()	Parenthesis calculation
OCT	Octal mode		

- The minus sign of the mantissa is floating minus.
- The arithmetic key operation in clouding Y^X or $x\sqrt{Y}$ has same sequence as mathematical equation. 6 pending operations are allowed and () are up to continuous 15 levels.
- Fractional number calculation.
- It is possible to convert mutually between decimal, binary, octal and hexadecimal, and the 4 operations in arithmetic in binary, octal and hexadecimal.



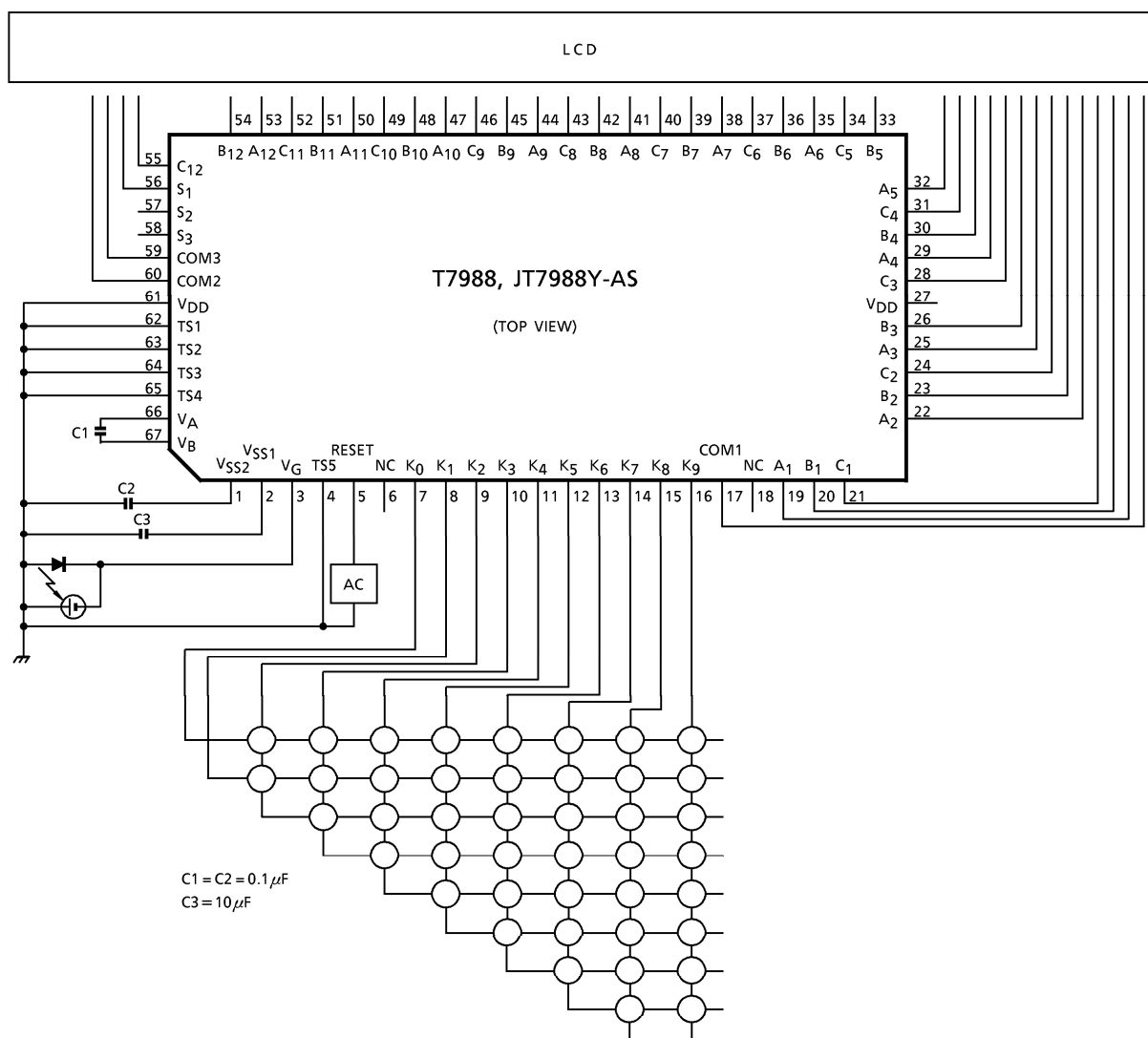
Weight : 1.20g (Typ.)

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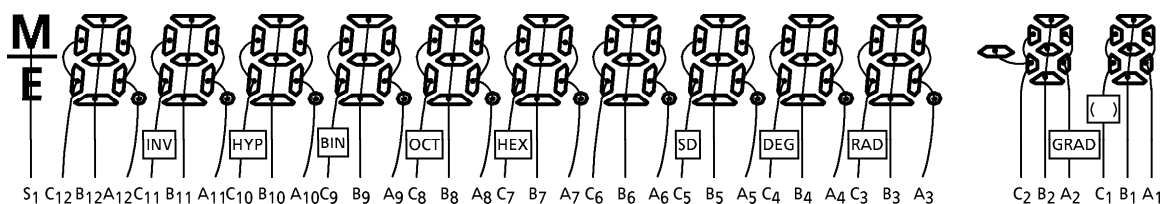
- One independent accumulating memory.
- It is possible to convert or fix the display number system by FLO (Floating) , SCI (Scientific) or ENG (Engineering) key.
- It is possible to specify decimal part digits (0~9) by FIX key.
- Direct drive for FEM LCD (1/2 prebias, 1/3 duty) .
- Automatic power on clear.
- Low power consumption. $V_G = -1.5V$ single power supply.
- The 67 pin flat package is used.

SYSTEM BLOCK DIAGRAM

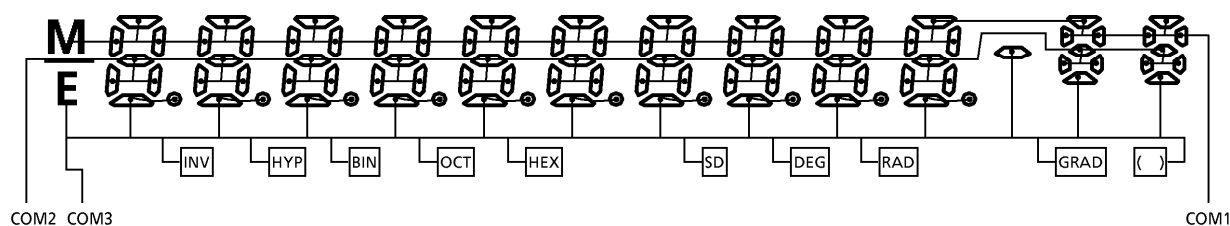


CONNECTION OF LCD

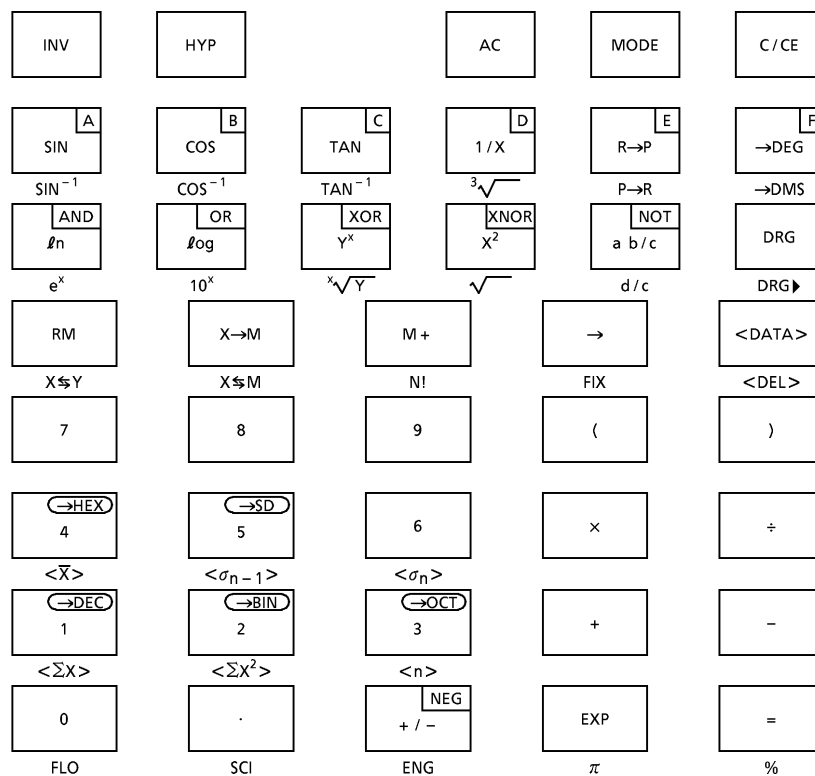
SEGMENT



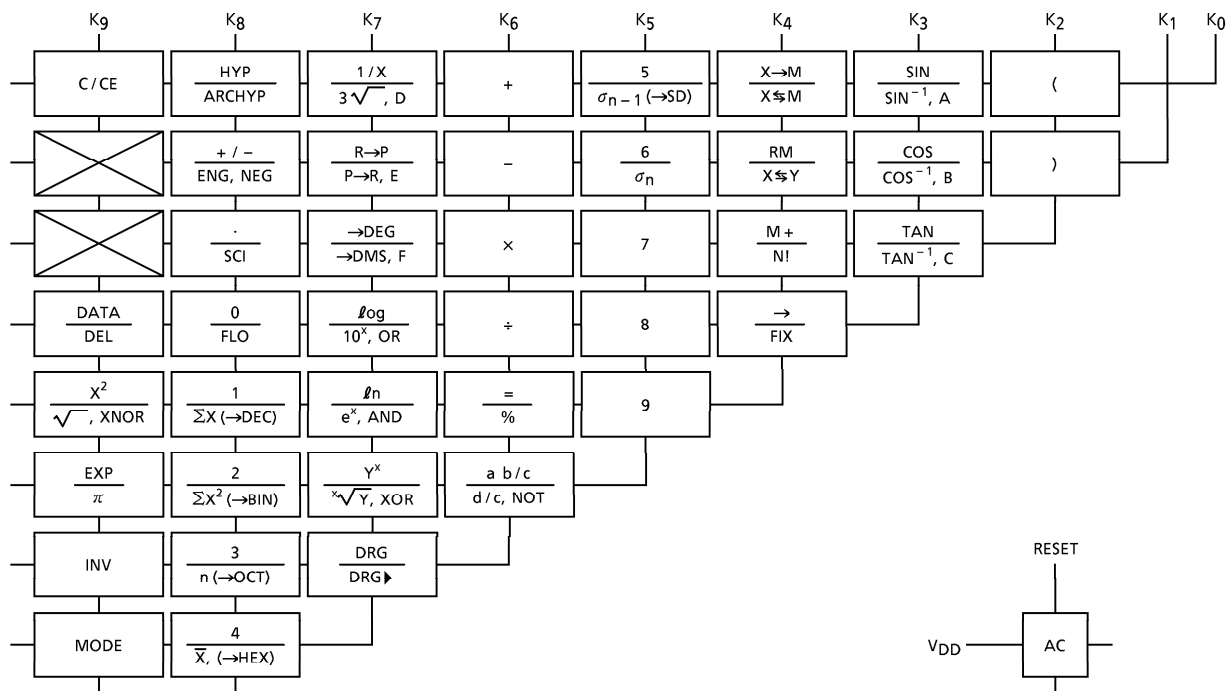
COMMON



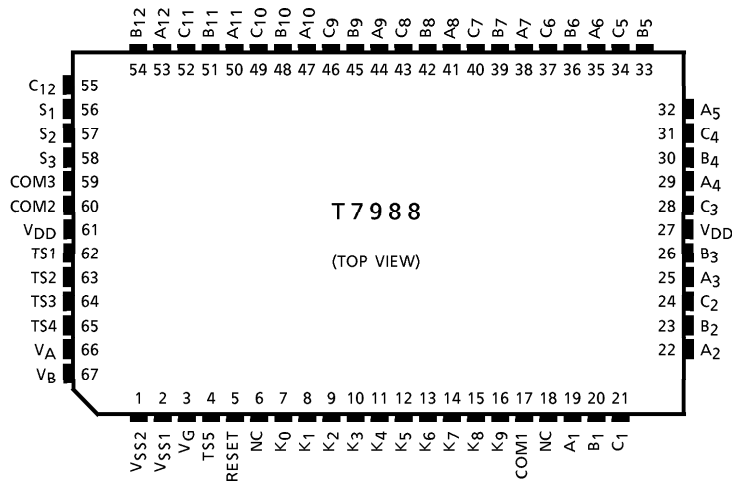
SET KEY LAYOUT (Example)



KEY LAYOUT



PIN LAYOUT



SPECIFICATION OF CALCULATOR

Speed of calculation

Key on 10ms

Key off 33.8ms

$f\phi_{WAIT} = 9\text{kHz}$, $f\phi_{op} = 24\text{kHz}$

The calculation speed doesn't include the key on or off time.

ITEM	OPERATION			CALCULATION SPEED (ms)
Number	DEC		5	26
			5	25
	HEX		A	26
			A	25
Function	DEC		+	69
			×	73
	HEX		-	172
			÷	176
4 operation	DEC	1 + 2	+	97
		1 0 0 0 0 0 0 0 0 0 - 1	-	104
		5 × 9	×	104
		5 5 5 5 5 × 9 9 9 9 9	×	120
	HEX	5 ÷ 9	÷	157
		5 5 5 5 5 ÷ 9 9 9 9 9	÷	193
		A B C + D E F	+	291
		A B C - D E F	-	479
$Y^X, \sqrt[X]{Y}$		A B C × D E F	×	334
		A B C ÷ D E F	÷	324
SIN	DEG	3 Y ^x 4	=	842
	RAD	3 ^x √Y 4	=	872
	GRAD			
COS	DEG	3 0	SIN	798
	RAD	$\pi \div 6 =$	SIN	764
	GRAD	1 0 0 ÷ 3 =	SIN	1161
TAN	DEG	6 0	COS	809
	RAD	$\pi \div 3 =$	COS	1031
	GRAD	200 ÷ 3 =	COS	1176
SIN ⁻¹	DEG	4 5	TAN	386
	RAD	$\pi \div 4 =$	TAN	143
	GRAD	5 0	TAN	154
COS ⁻¹	DEG	0. 5	SIN ⁻¹	836
	RAD	0. 5	SIN ⁻¹	653
	GRAD	0. 5	SIN ⁻¹	825
TAN ⁻¹	DEG	0. 5	COS ⁻¹	1069
	RAD	0. 5	COS ⁻¹	762
	GRAD	0. 5	COS ⁻¹	1057
Ln	DEG	1	TAN ⁻¹	237
	RAD	1	TAN ⁻¹	147
	GRAD	1	TAN ⁻¹	236
Log		2 0	ln	160
		2 0	log	332

ITEM	OPERATION			CALCULATION SPEED (ms)
e ^x		2 0	e ^x	315
10 ^x		1. 2 3	10 ^x	380
		1 0	10 ^x	137
X!		6 9	N!	970
HYP		3 hyp	SIN	623
		3 hyp	COS	627
		3 hyp	TAN	766
ARC HYP		3 hyp ⁻¹	SIN	607
		3 hyp ⁻¹	COS	677
		0.5 hyp ⁻¹	TAN	574
X ²		2 0	X ²	64
$\sqrt{\quad}$		2 0	$\sqrt{\quad}$	217
1 / X		2 0	1 / X	80
$\sqrt[3]{\quad}$		2 0	$\sqrt[3]{\quad}$	604
Mutual Conversion	DEC	1 2 3	→BIN	118
		1 2 3 4 5	→OCT	134
		1 2 3 4 5	→HEX	120
	BIN	1 0 1 0 1	→DEC	93
	OCT	1 2 3 4 5	→DEC	112
HEX	A B C D E	→DEC	181	
→DEG		1.2 3 4 5	→DEG	265
→DMS		1.2 3 4 5	→DMS	304
R→P	DEG	$\sqrt[3]{\quad}$ X↔Y 1	R→P	920
	RAD	$\sqrt[3]{\quad}$ X↔Y 1	R→P	723
	GRAD	$\sqrt[3]{\quad}$ X↔Y 1	R→P	919
P→R	DEG	2 X↔Y 3 0	P→R	1543
	RAD	2 X↔Y 30 DRG▶	P→R	1461
	GRAD	2 X↔Y 30 DRG▶ DRG▶	P→R	2089
→RAD	DEG	3 6 0	DRG▶	147
→GRAD	RAD	2 × π =	DRG▶	100
→DEG	GRAD	4 0 0	DRG▶	71
Memory		1 2 3	X→M	47
		1 2 3 X → M	M +	65
		1 2 3 X → M	RM	41
		1 2 3 X → M	X↔M	54
%		1 2 3 + 4 5 6	%	86
		1 2 3 - 4 5 6	%	86
		1 2 3 × 4 5 6	%	56
		1 2 3 ÷ 4 5 6	%	56
Exchange		1 2 3 + 4 5 6	X↔Y	52
Shift		1 2 3	→	27

ITEM	OPERATION				CALCULATION SPEED (ms)		
Statistic Calculation	1 DATA	2 DATA	3 DATA 8 DATA	9 DATA	125	
	The above-mentioned data					n	56
						\bar{X}	74
						ΣX	51
						ΣX^2	52
						σ_{n-1}	300
σ_n						347	
Logic operation	HEX	A B C AND D E F	=	603			
		A B C OR D E F	=	650			
		A B C XOR D E F	=	568			
		A B C XNOR D E F	=	961			
		A B C	NOT	394			
NEG	HEX	A B C	NEG	375			
Fractional number calculation	Function	2 ab/c 3 6 ab/c 2 3 4	-	249			
		2 ab/c 3 6 ab/c 2 3 4	÷	253			
	4-operation	2 $\frac{36}{J}$ 234 + 3 $\frac{45}{J}$ 345	=	536			
		2 $\frac{36}{J}$ 234 - 3 $\frac{45}{J}$ 345	=	512			
		2 $\frac{36}{J}$ 234 × 3 $\frac{45}{J}$ 345	=	498			
2 $\frac{36}{J}$ 234 ÷ 3 $\frac{45}{J}$ 345	=	562					

OPERATION RANGE AND ACCURACY

FUNCTION	ANGLE UNIT	OPERATION RANGE	UNDER FLOW AREA	NORMAL ACCURACY
SIN X	DEG	$0 \leq X \leq 4.499999999 \times 10^{10}$	$0 \leq X \leq 5.729577951 \times 10^{-98}$	10 digits ± 1
	RAD	$0 \leq X \leq 785398163.3$	—	
	GRAD	$0 \leq X \leq 4.999999999 \times 10^{10}$	$0 \leq X \leq 6.366197723 \times 10^{-98}$	
COS X	DEG	$0 \leq X \leq 4.500000008 \times 10^{10}$	—	
	RAD	$0 \leq X \leq 785398164.9$	—	
	GRAD	$0 \leq X \leq 5.000000009 \times 10^{10}$	—	
TAN X	DEG	SAME AS SINX except for $ X = (2n - 1) \cdot 90$	SAME AS SINX	
	RAD	SAME AS SINX except for $ X = (2n - 1) \cdot \pi / 2$	SAME AS SINX	
	GRAD	SAME AS SINX except for $ X = (2n - 1) \cdot 100$	SAME AS SINX	
SIN ⁻¹ X	DEG	$0 \leq X \leq 1$	$0 \leq X \leq 1.570796326 \times 10^{-99}$	
	RAD	$0 \leq X \leq 1$	—	
	GRAD	$0 \leq X \leq 1$	$0 \leq X \leq 1.570796326 \times 10^{-99}$	
COS ⁻¹ X	DEG	SAME AS SIN ⁻¹ X	—	
	RAD	SAME AS SIN ⁻¹ X	—	
	GRAD	SAME AS SIN ⁻¹ X	—	
TAN ⁻¹ X	DEG	$0 \leq X \leq 9.999999999 \times 10^{99}$	SAME AS SIN ⁻¹ X	
	RAD	$0 \leq X \leq 9.999999999 \times 10^{99}$	—	
	GRAD	$0 \leq X \leq 9.999999999 \times 10^{99}$	SAME AS SIN ⁻¹ X	

FUNCTION	OPERATION RANGE	UNDER FLOW AREA	NORMAL ACCURACY
LN X	0 < X	—	10 digits ± 1
LOG X	0 < X	—	
e ^x	- 9.99999999 × 10 ⁹⁹ ≤ X ≤ 230.2585092	- 9.99999999 × 10 ⁹⁹ ≤ X ≤ - 227.9559243	
10 ^x	- 9.99999999 × 10 ⁹⁹ ≤ X ≤ 99.99999999	- 9.99999999 × 10 ⁹⁹ ≤ X ≤ - 99.00000001	
X!	0 ≤ X ≤ 69 (INTEGER)	—	
$\frac{1}{X}$	1 × 10 ⁻⁹⁹ ≤ X ≤ 9.99999999 × 10 ⁹⁹	1.000000001 × 10 ⁹⁹ ≤ X ≤ 9.99999999 × 10 ⁹⁹	
X ²	0 ≤ X ≤ 9.99999999 × 10 ⁴⁹	≤ X ≤ 3.162277660 × 10 ⁻⁵⁰	
\sqrt{X}	0 ≤ X ≤ 9.99999999 × 10 ⁹⁹	—	
$\sqrt[3]{X}$	0 ≤ X ≤ 9.99999999 × 10 ⁹⁹	—	
DMS → DEG	0 ≤ X ≤ 9.99999999 × 10 ⁹	—	
DEG → DMS	0 ≤ X ≤ 9999999.999	0 ≤ X ≤ 1.388888888 × 10 ⁻⁶	lowest digits ± 1
SINH X	0 ≤ X ≤ 230.2585092	—	10 digits ± 1
COSH X	0 ≤ X ≤ 230.2585092	—	
TANH X	0 ≤ X ≤ 9.99999999 × 10 ⁹⁹	—	
SINH ⁻¹ X	0 ≤ X ≤ 4.99999999 × 10 ⁹⁹	—	
COSH ⁻¹ X	1 ≤ X ≤ 4.99999999 × 10 ⁹⁹	—	
TANH ⁻¹ X	0 ≤ X ≤ 9.99999999 × 10 ⁻¹	—	
R → P (xy → γθ)	x , y ≤ 9.99999999 × 10 ⁴⁹ (x ² + y ²) ≤ 9.99999999 × 10 ⁹⁹ $\frac{Y}{X}$; SAME AS TAN ⁻¹ X	$\frac{Y}{X}$; SAME AS TAN ⁻¹ X	
P → R (γθ → xy)	0 ≤ γ ≤ 9.99999999 × 10 ⁹⁹ θ ; SAME AS SIN X, COS X	θ ; SAME AS SIN X, COS X	
DEG → RAD	0 ≤ X ≤ 9.99999999 × 10 ⁹⁹	0 ≤ X ≤ 5.729577951 × 10 ⁻⁹⁸	
RAD → GRAD	0 ≤ X ≤ 1.570796326 × 10 ⁹⁸	—	
GRAD → DEG	0 ≤ X ≤ 9.99999999 × 10 ⁹⁹	0 ≤ X ≤ 1.111111111 × 10 ⁻⁹⁹	
Y ^X	- 9.99999999 × 10 ⁹⁹ ≤ X · LN Y ≤ 230.2585092 (1) Y > 0 ··· The above-mentioned operation range. (2) Y < 0 ··· X (Integer) or, 1 / X (Odd, X ≠ 0) ··· The above-mentioned operation range. (3) Y = 0 ··· 0 < X	- 9.99999999 × 10 ⁹⁹ ≤ X · LN Y ≤ - 227.9559243	10 digits ± 1

FUNCTION	OPERATION RANGE	UNDER FLOW AREA	NORMAL ACCURACY
$x\sqrt{Y}$	$-9.999999999 \times 10^{99}$ $\leq \frac{1}{X} \cdot \text{LN } Y \leq 230.2585092$	$-9.999999999 \times 10^{99}$ $\leq \frac{1}{X} \cdot \text{LN } Y \leq -227.95593243$	10 digits ± 1
	(1) $Y > 0$...The above-mentioned operation range. (2) $Y < 0$...X (Odd) or $1/X$ (Integer, $X \neq 0$) ...The above-mentioned operation range. (3) $Y = 0$... $0 < X$		
→DEC	Operation range		—
	The following operation range after the conversion. $0 \leq X \leq 9999999999$		
→BIN	The following operation range after the conversion. $1000000000 \leq X \leq 1111111111$ $0 \leq X \leq 1111111111$		—
→OCT	The following operation range after the conversion. $4000000000 \leq X \leq 7777777777$ $0 \leq X \leq 3777777777$		—
→HEX	The following operation range after the conversion. $\text{FDABF41CO1} \leq X \leq \text{FFFFFFFF}$ $0 \leq X \leq \text{2540BE3FF}$		—
AND OR XOR XNOR	BIN ; $1000000000 \leq X \leq 1111111111$ $0 \leq X \leq 1111111111$ OCT ; $4000000000 \leq X \leq 7777777777$ $0 \leq X \leq 3777777777$ HEX ; The following operation range after the operation. $\text{FDABF41CO1} \leq X \leq \text{FFFFFFFF}$ $0 \leq X \leq \text{2540BE3FF}$		—
NOT	BIN ; SAME AS AND OCT ; SAME AS AND HEX ; $\text{FDABF41CO1} \leq X \leq \text{FFFFFFFF}$ $0 \leq X \leq \text{2540BE3FE}$		—
NEG	BIN ; $1000000001 \leq X \leq 1111111111$ $0 \leq X \leq 1111111111$ OCT ; $4000000001 \leq X \leq 7777777777$ $0 \leq X \leq 3777777777$ HEX ; $\text{FDABF41CO1} \leq X \leq \text{FFFFFFFF}$ $0 \leq X \leq \text{2540BE3FF}$		—

FUNCTION		OPERATION RANGE	NORMAL ACCURACY
Statistic	DATA DEL	$ x \leq 9.999999999 \times 10^{49}$ $ \sum x \leq 9.999999999 \times 10^{99}$ $\sum x^2 \leq 9.999999999 \times 10^{99}$ $0 \leq n \leq 9999999999$. n = Integer	10 digits ± 1
	\bar{x}	n ≠ 0	
	σ_{n-1}	n ≠ 1, n ≠ 0 $0 \leq \frac{\sum X^2 - \{(\sum X)^2 / n\}}{n - 1} \leq 9.999999999 \times 10^{99}$	
	σ_n	n ≠ 0 $0 \leq \frac{\sum X^2 - \{(\sum X)^2 / n\}}{n} \leq 9.999999999 \times 10^{99}$	

MAXIMUM RATINGS (Ta = 25°C)

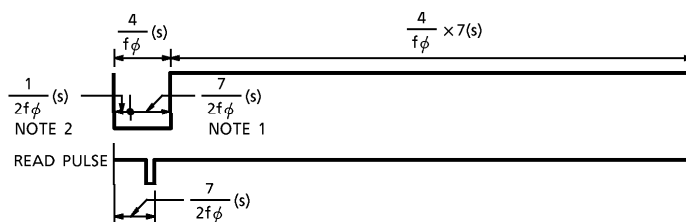
PARAMETER	SYMBOL	RATING	UNIT
Supply Voltage	V _G	+ 0.3 ~ - 2.2	V
Input Voltage	V _{IN}	+ 0.3 ~ V _G - 0.3	V
Operating Temperature	T _{opr}	0 ~ 40	°C
Storage Temperature	T _{stg}	- 55 ~ 125	°C

ELECTRICAL CHARACTERISTICS (V_G = - 1.5V ± 0.2V, V_{SS2} = - 3.0 ± 0.4V, V_{DD} = 0V, Ta = 25°C)

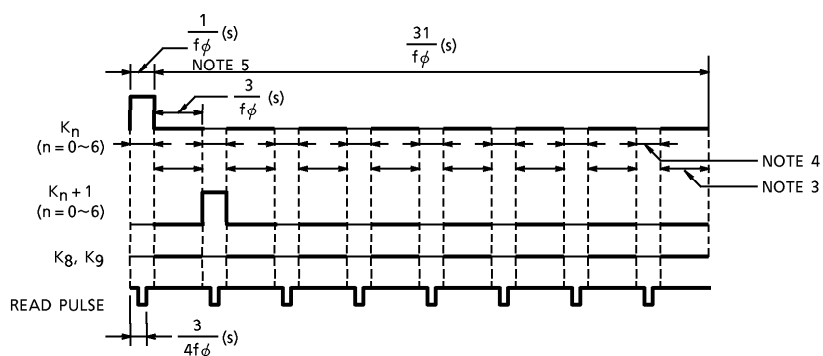
PARAMETER	SYMBOL	TEST CIR-CUIT	PIN NAME	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
Operating Voltage	V _G	—	—	—	- 1.2	- 1.5	- 2.0	V
Supply Current (I)	I _{DD} WAIT	—	—	V _G = - 1.5V, wait	—	2.0	3.0	μA
Supply Current (II)	I _{DD} OP	—	—	V _G = - 1.2V, operate	—	4.5	7.0	μA
Oscillating Frequency (I)	F _φ WAIT	—	—	V _G = - 1.5V, wait	5.4	9.0	12.6	kHz
Oscillating Frequency (II)	F _φ OP	—	—	V _G = - 1.5V, operate	14.4	24.0	33.6	kHz
Frame Frequency	f _F	—	—	V _G = - 1.5V, wait	56.3	93.8	131.3	Hz
"1" Input Voltage	V _{IH}	—	K ₂ ~K ₉ RESET	—	V _G + 0.4	—	V _G	V
"0" Input Voltage	V _{IL}	—	K ₂ ~K ₉ RESET	—	V _{DD}	—	- 0.4	V
"1" Output Voltage	V _{OH} (I)	—	SEGMENT COM1~3	—	V _{SS2} + 0.2	—	V _{SS2}	V
"0" Output Voltage	V _{OL} (I)	—	SEGMENT COM1~3	—	V _{DD}	—	- 0.2	V

PARAMETER	SYMBOL	TEST CIR-CUIT	PIN NAME	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
"M" Output Voltage	V _{OM}	—	COM1~3	—	V _{SS1} + 0.2	—	V _{SS1} - 0.2	V
"1" Output Voltage	V _{OH} (II)	—	K ₀ ~K ₉ RESET	—	V _{SS1} + 0.2	—	V _{SS1}	V
"0" Output Voltage	V _{OL} (II)	—	K ₀ ~K ₉ RESET	—	V _{DD}	—	- 0.2	V
"1" Output Resistance	R _{OH}	—	SEGMENT COM1~3	V _{OUT} = V _{SS2} + 0.5V	—	—	70	kΩ
"0" Output Resistance	R _{OL}	—	SEGMENT COM1~3	V _{OUT} = - 0.5V	—	—	70	kΩ
RESET Pull Up Resistance (I)	R _{RSETH} (I)	—	RESET	V _{OUT} = 0V (NOTE 1)	156	260	364	kΩ
RESET Pull Up Resistance (II)	R _{RSETH} (II)	—	RESET	V _{OUT} = 0V (NOTE 2)	18	75	300	kΩ
Key Pull Up Resistance (I)	R _{KEYH} (I)	—	K ₀ ~K ₉	V _{OUT} = V _G + 0.5V (NOTE 3)	—	—	500	kΩ
Key Pull Up Resistance (II)	R _{KEYH}	—	K ₀ ~K ₉	V _{OUT} = 0V (NOTE 4)	60	300	1500	kΩ
Key RESET Pull Down Resistance	R _{KEYL} RESETL	—	K ₀ ~K ₉ RESET	V _{OUT} = - 0.5V (NOTE 5)	—	—	25	kΩ

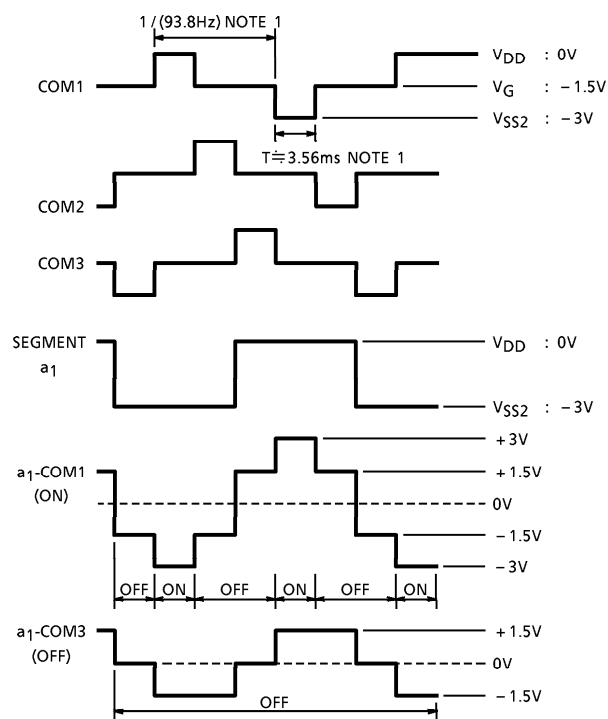
NOTE 1, 2, 5 (RESET Waveform, 1-cycle)



NOTE 3, 4, 5 (KEY Waveform, 1-cycle)



WAVEFORMS FOR DISPLAY



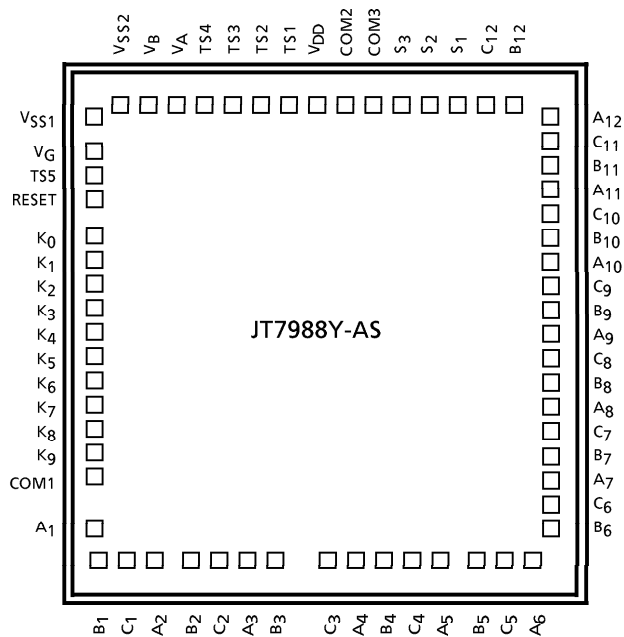
PAD LOCATION TABLE

(μm)

No.	NAME	X POINT	Y POINT
1	VSS2	- 1215	1536
2	VSS1	- 1404	1494
3	VG	- 1404	1260
4	TS5	- 1404	1059
5	RESET	- 1404	873
6	K ₀	- 1404	612
7	K ₁	- 1404	450
8	K ₂	- 1404	288
9	K ₃	- 1404	126
10	K ₄	- 1404	- 36
11	K ₅	- 1404	- 198
12	K ₆	- 1404	- 360
13	K ₇	- 1404	- 522
14	K ₈	- 1404	- 684
15	K ₉	- 1404	- 846
16	COM1	- 1404	- 1008
17	A ₁	- 1404	- 1377
18	B ₁	- 1326	- 1539
19	C ₁	- 1164	- 1539
20	A ₂	- 1002	- 1539
21	B ₂	- 758	- 1539
22	C ₂	- 596	- 1539
23	A ₃	- 434	- 1539
24	B ₃	- 272	- 1539
25	C ₃	127	- 1539
26	A ₄	289	- 1539
27	B ₄	451	- 1539
28	C ₄	613	- 1539
29	A ₅	775	- 1539
30	B ₅	1002	- 1539
31	C ₅	1164	- 1539
32	A ₆	1326	- 1539

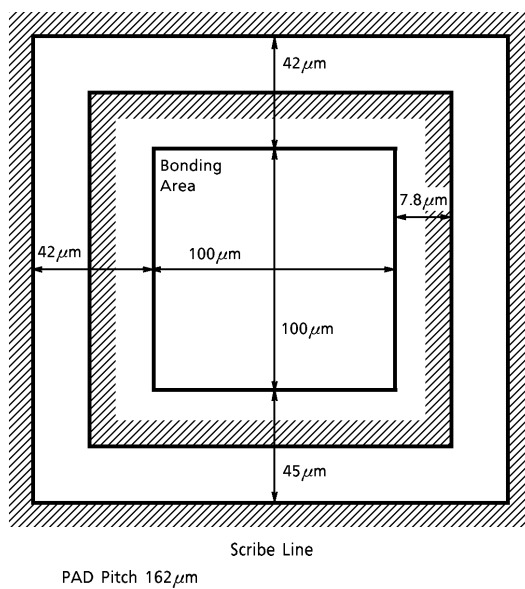
No.	NAME	X POINT	Y POINT
33	B ₆	1404	- 1377
34	C ₆	1404	- 1170
35	A ₇	1404	- 1008
36	B ₇	1404	- 846
37	C ₇	1404	- 684
38	A ₈	1404	- 522
39	B ₈	1404	- 360
40	C ₈	1404	- 198
41	A ₉	1404	- 36
42	B ₉	1404	126
43	C ₉	1404	288
44	A ₁₀	1404	450
45	B ₁₀	1404	612
46	C ₁₀	1404	774
47	A ₁₁	1404	936
48	B ₁₁	1404	1098
49	C ₁₁	1404	1260
50	A ₁₂	1404	1494
51	B ₁₂	1215	1536
52	C ₁₂	1053	1536
53	S ₁	869	1536
54	S ₂	707	1536
55	S ₃	545	1536
56	COM3	383	1536
57	COM2	218	1536
58	VDD	0	1536
59	TS1	- 218	1536
60	TS2	- 380	1536
61	TS3	- 542	1536
62	TS4	- 729	1536
63	VA	- 891	1536
64	VB	- 1053	1536

CHIP LAYOUT



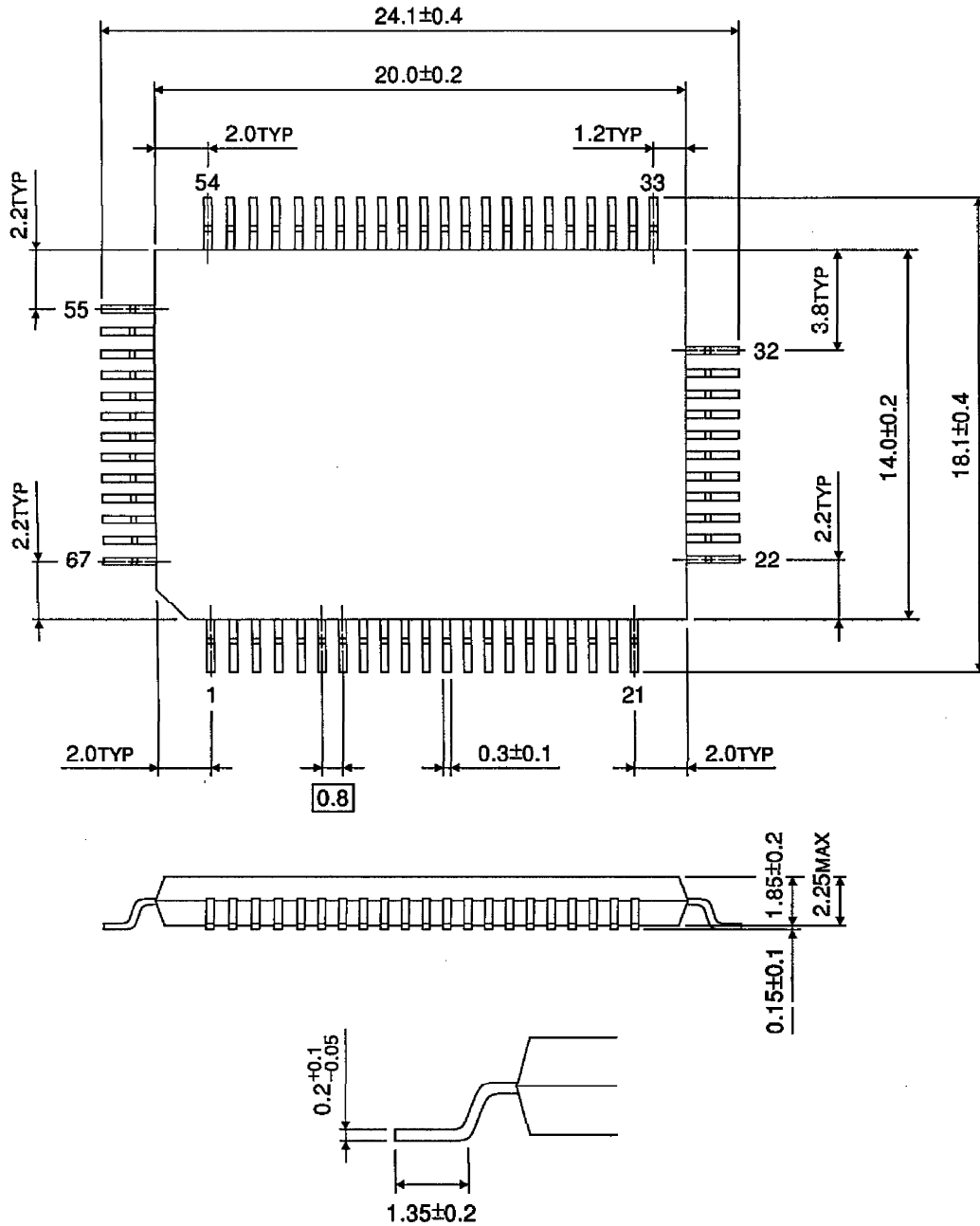
Chip size : 3.08×3.41 [mm]
 Chip thickness : 450±20 [μm]
 Substrate : VDD

PAD LAYOUT



OUTLINE DRAWING
QFP67-P-1420-0.80

Unit : mm



Weight : 1.20g (Typ.)

GENERAL SPECIFICATION FOR CALCULATOR LSI BARE CHIP

1. Purpose

This is to specify the quality standard for the integrated circuit produced by TOSHIBA CORPORATION (hereinafter referred as to VENDOR) to be delivered to PURCHASER.

2. Definition

This specification applies only to the calculator LSI bare chip produced by VENDOR and purchased by PURCHASER and defined the general specification items.

3. Priority of specifications

When the discrepancies or questions happen to the specifications and instructions provided by VENDOR, the priority shall be ranked as follows.

- 1) Individual specification for the calculator LSI bare chip.
(Both PURCHASER and VENDOR are confirmed by the special sheets.)
- 2) General specifications for the calculator LSI bare chip.
- 3) Other related specifications and standards.

4. Characteristics

To be shown in the individual specification sheets.

The individual specification shall consist of the following 4 items in principle.

- 1) Rated specifications.
- 2) Electrical characteristics.
- 3) Pin configuration & mechanical dimensions.
- 4) Others.

5. Inspection of product for delivery

5.1 Inspection lot

- a) Inspection lot shall consist of products produced by same material under same design, through same production process, and same facilities and assured same quality by same quality assurance method, and lot number shall be put on all trays to be able to trace the lot history.
- b) The quantity of products per Inspection lot shall consist of all the same VENDOR's lot number.

5.2 Sampling plan

Statistical sampling and inspection shall be in accordance with MIL-STD-105D single sampling plans for normal inspections, general inspection level II.

The acceptable quality level (AQL) shall be specified in following table :

TEST ITEM	AQL (%)
Electrical	2.5
Visual	4.0

5.3 Electrical criteria

Criteria of Electrical Characteristics are prescribed in Attachment-1.

5.4 Visual criteria

Visual Criteria are prescribed in Attachment-2.

6. Incoming inspection**6.1 General**

- a) PURCHASER's incoming inspection should be done within 15 days after PURCHASER receives the quantity of products in principle.
- b) PURCHASER shall report the results of incoming inspection to VENDOR and provide VENDOR with detailed data in failure rate and items regarding VENDOR's lot number respectively, if VENDOR demands the report from PURCHASER.

6.2 Inspection procedure

PURCHASER should do his incoming inspection according to the following procedure.

- a) First : Visual inspection should be done.
- b) Next : Electrical and other inspection should be done under condition with bare chip before going into PURCHASER's process.

7. Treatment for defective lot and products

Regarding the defective lot and defective products which are found through PURCHASER's incoming inspection, PURCHASER can be returned to VENDOR with detailed description on failures concerned.

However, if VENDOR cannot receive the defective items within 30 days after PURCHASER's incoming inspection, VENDOR should be able to make no reference to the defective problem.

8. Packing and labeling

- a) Dice shall be placed in die tray with the top metalization facing up in order.
- b) In principle, a pile consists of 5 trays and several piles are packed in a package. These piles and packages are indicated with printed labels as shown below.

Date	
Name	
Lot No.	
Net	
TOSHIBA MADE IN JAPAN	

- c) PURCHASER shall return these packing materials to VENDOR on VENDOR's demand.

9. Storage criteria

Solid state chips, unlike packaged devices, are non-hermetic devices normally fragile and small in physical size, and therefore, require special handling considerations as follows :

- 9.1 Chips must be stored under proper conditions to insure that they are not subjected to a moist and/or contaminated atmosphere that alter their electrical, physical, or mechanical characteristics.
After the shipping container is opened, the chips must be stored under the following conditions :
 - A. Storage temperature, 40°C max.
 - B. Relative humidity, 50% max.
 - C. Clean, dust-free environment.
- 9.2 The user must exercise proper care when handling chips or wafers to prevent even the slightest physical damage to the chip.
- 9.3 During mounting and lead bounding of chips the user must use proper assembly techniques to obtain proper electrical, thermal, and mechanical performance.
- 9.4 After the chip has been mounted and bounded, any necessary procedure must be followed by the user to insure that these non-hermetic chips are not subjected to moist or contaminated atmosphere which might cause the development of electrical conductive paths across the relatively small insulating surfaces.
In addition, proper consideration must be given to the protection of these devices from other harmful environments which could conceivably adversely affect their proper performance.

10. Handling criteria

The user should find the following suggested precautions helpful in handling chips.

In any event, because of the extremely small size and fragile nature of chips, care should be taken in handling these devices.

10.1 Grounding

- a) Bonders, pellet pickup tools, table tops, trim and form tools, sealing equipment, and other equipment used in chip handling should be properly grounded.
- b) Operator should be properly grounded.

10.2 In-process handling

- a) Assemblies or subassemblies of chips should be transported and stored in conductive carriers.
- b) All external leads of the assemblies or subassemblies should be shorted together.

VISUAL INSPECTION CRITERIA

1. Visual inspection magnification shall be 40 × in principle.

2. Defects defined :

2.1 Thickness

See the technical data sheet.

2.2 Chip and crack

A die shall be rejected if :

- a) Any crack of chip extends greater than 35 μ m in length into the inside of the scribble line. (see Fig.1)

2.3 Metallization

A die shall be rejected if :

- a) More than 25% of the designed area of the metallization is missing at any bonding pad.
- b) There is a short or break which affects electrical characteristics in any lead pattern. (see Fig.2)

2.4 Glass protection coat

A die shall be rejected if :

- a) It exhibits glass protection coat which covers more than 25% of any active bonding pad.

2.5 Attached foreign material

A die shall be rejected if :

- a) A die is covered by stains or attached foreign material which size is more than 5 times as large as a bonding pad area.
- b) It exhibits residual ink, stains or attached foreign material which covers more than 20% of any active bonding pad. (see Fig.3)

2.6 Others

A die shall be rejected if :

- a) There have no evident probed impression on the bonding pads.
- b) A inked die, defective die, is intermized.

3. Limit samples should be fixed, if necessary.

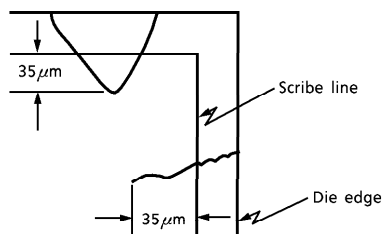


Fig.1

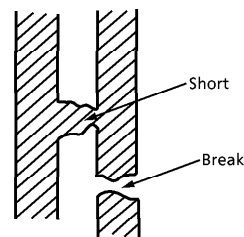


Fig.2 Lead pattern

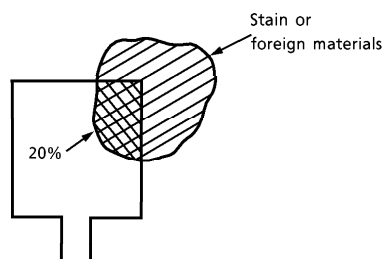
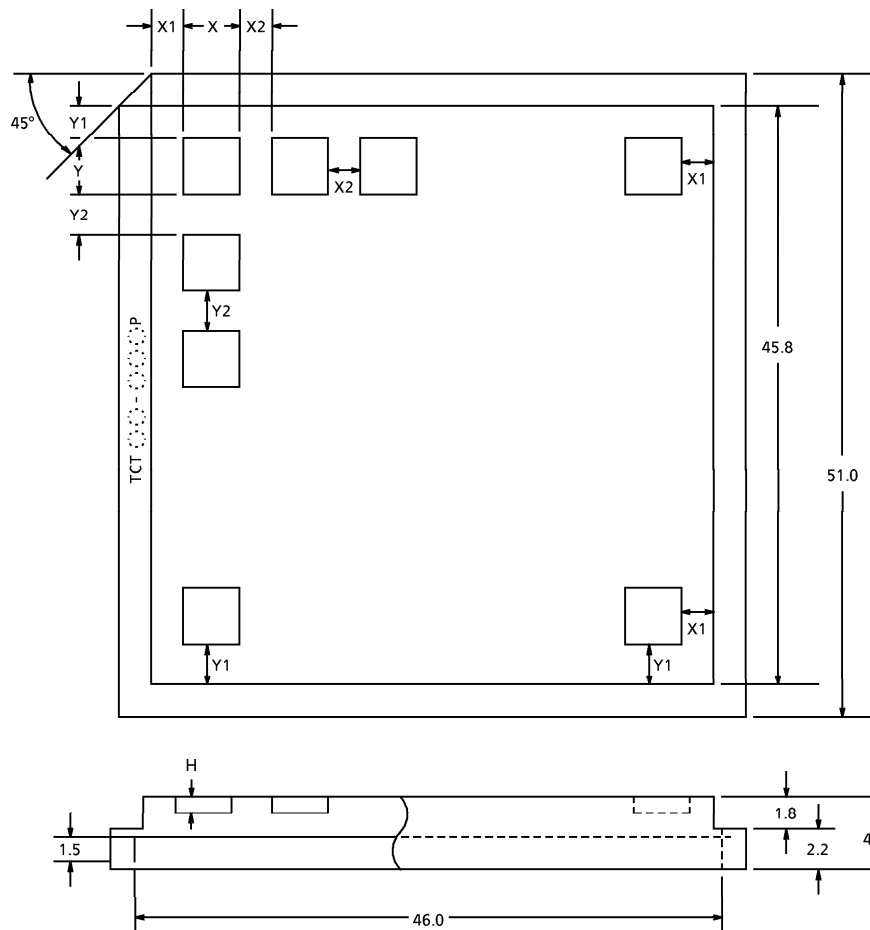


Fig.3

OUTSIDE DIMENSIONS OF CHIP TRAY



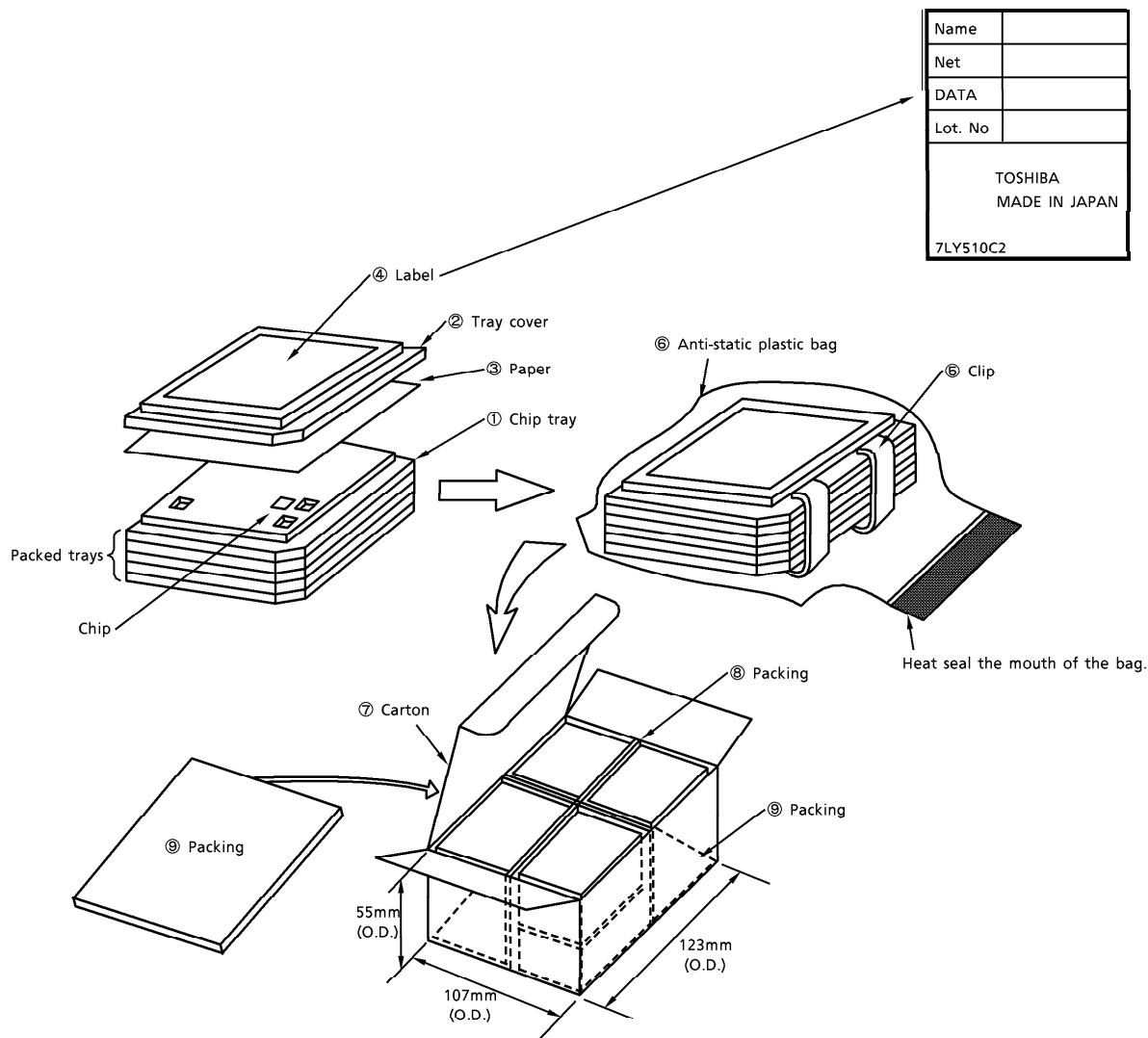
Unit : mm

CHIP NAME	TRAY NAME	X	Y	(H)	No. OF POCKETS	X1	X2	Y1	Y2
JT7988Y-AS	TCT38-060P	3.80	3.80	0.60	10 × 10 (100)	1.200	0.600	1.200	0.600

Tray material :

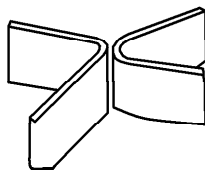
Carbon-containing polypropylene

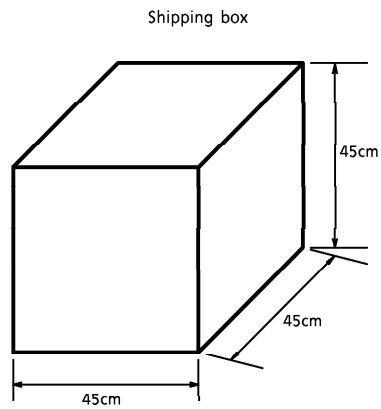
PACKING METHOD-1



Name	
Net	
DATA	
Lot. No	
TOSHIBA MADE IN JAPAN	
7LY510C2	

Place eight bags of chip trays in each carton box ⑦. Lay one sheet of packing ⑨ (7UF44F) before closing the lid of the cart box. (See the diagram above.)
 Prepare packing ⑨ by cutting 7UF44F into halves and folding each in half as shown below ; use them as inner partitions.



PACKING METHOD-2

- Inner box : Containing 20 boxes
- Weight : Approx. 15kg (including packing material)
- Material : Corrugated cardboard
- IC contents : $36 \times 5 \times 8 \times 20 = 28.8\text{kpcs}$.